

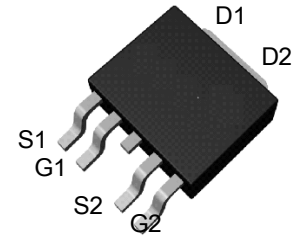
Description

The XPX55NP04FX uses advanced trench technology

to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a

Battery protection or in other Switching application.

Pin Description



Top View of TO-252-4

Features

- N Channel**

40V/55A,

$$R_{DS(ON)} = 6.3m\Omega \text{ (typ.) @ } V_{GS} = 10V$$

$$R_{DS(ON)} = 9m\Omega \text{ (typ.) @ } V_{GS} = 4.5V$$

- P Channel**

-40V/-50A,

$$R_{DS(ON)} = 11m\Omega \text{ (typ.) @ } V_{GS} = -10V$$

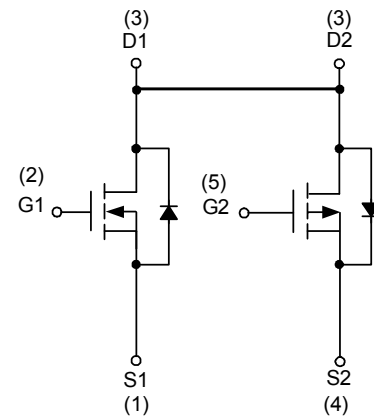
$$R_{DS(ON)} = 15m\Omega \text{ (typ.) @ } V_{GS} = -4.5V$$

- 100% UIS Tested

- Reliable

Lead Free Available (RoHS Compliant)

Applications



N-Channel MOSFET

P-Channel MOSFET

Product ID	Pack	Marking	Qty(PCS)
XPX55NP04FX	TO-252-4L	XPX55NP04FX XXX YYYY	2500

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	N-Ch	P-Ch	Units
V_{DS}	Drain-Source Voltage	40	-40	V
V_{GS}	Gate-Source Voltage	± 20	± 20	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	55	-50	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	41	-38	A
I_{DM}	Pulsed Drain Current ²	170	-150	A
EAS	Single Pulse Avalanche Energy ³	289	378	mJ
I_{AS}	Avalanche Current	42	-50	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation ⁴	58	61.3	W
T_{STG}	Storage Temperature Range	-55 to 150		$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150		$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	62.5		$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	2.3		$^\circ\text{C/W}$

N-Electrical Characteristics (T_c=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	40	44	---	V
ΔBVDSS/ΔT _J	BVDSS Temperature Coefficient	Reference to 25°C, I _D =1mA	---	0.034	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =10A	---	6.3	9.0	mΩ
		V _{GS} =4.5V, I _D =8A	---	9.0	12	
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.0	1.6	2.5	V
ΔVGS(th)	V _{GS(th)} Temperature Coefficient		---	-4.96	---	mV/°C
IDSS	Drain-Source Leakage Current	V _{DS} =32V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =32V, V _{GS} =0V, T _J =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
gfs	Forward Transconductance	V _{DS} =5V, I _D =10A	---	40	---	S
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	1.6	---	Ω
Q _g	Total Gate Charge (4.5V)	V _{DS} =20V, V _{GS} =4.5V, I _D =10A	---	18.8		nC
Q _{gs}	Gate-Source Charge		---	4.7		
Q _{gd}	Gate-Drain Charge		---	8.2		
Td(on)	Turn-On Delay Time	V _{DD} =15V, V _{GS} =10V , R _G =3.3Ω I _D =1A	---	14.3		ns
T _r	Rise Time		---	2.6		
Td(off)	Turn-Off Delay Time		---	77		
T _f	Fall Time		---	4.8		
Ciss	Input Capacitance	V _{DS} =15V, V _{GS} =0V, f=1MHz	---	2332		pF
Coss	Output Capacitance		---	193		
Crss	Reverse Transfer Capacitance		---	138		
IS	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	10.5	A
ISM	Pulsed Source Current ^{2,5}		---	---	42	A
VSD	Diode Forward Voltage ²	V _{GS} =0V, I _S =1A, T _J =25°C	---	---	1	V

Note :

- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The power dissipation is limited by 175°C junction temperature
- 4、 EAS condition: T_J=25°C, V_{DD}=32V, V_G= 10V, R_G=25Ω, L=0.1mH, I_{AS}= 25A
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

P-Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-40	-44	---	V
ΔBV _{DSS} /ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA	---	-0.023	---	V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-30A	---	11	16	mΩ
		V _{GS} =-4.5V , I _D =-20A	---	15	20	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.0	-1.6	-2.5	V
ΔV _{GS(th)}	V _{GS(th)} Temperature Coefficient		---	4.74	---	mV/°C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-40V , V _{GS} =0V , T _J =25°C	---	---	1	uA
		V _{DS} =-40V , V _{GS} =0V , T _J =55°C	---	---	5	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V	---	---	±100	nA
Q _g	Total Gate Charge (-4.5V)	V _{DS} =-20V , V _{GS} =-4.5V , I _D =-12A	---	25	---	nC
Q _{gs}	Gate-Source Charge		---	11	---	
Q _{gd}	Gate-Drain Charge		---	9.5	---	
T _{d(on)}	Turn-On Delay Time	V _{DD} =-15V, R _L =15Ω I _D =-1A, V _{GEN} =-10V, R _G =6Ω	---	48	---	ns
T _r	Rise Time		---	24	---	
T _{d(off)}	Turn-Off Delay Time		---	88	---	
T _f	Fall Time		---	9.6	---	
C _{iss}	Input Capacitance	V _{DS} =-20V , V _{GS} =0V , f=1MHz	---	2760	---	pF
C _{oss}	Output Capacitance		---	260	---	
C _{rss}	Reverse Transfer Capacitance		---	85	---	
I _S	Continuous Source Current ^{1,5}	V _G =V _D =0V , Force Current	---	---	-40	A
I _{SM}	Pulsed Source Current ^{2,5}		---	---	-90	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25°C	---	---	-1.3	V

Note :

- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The power dissipation is limited by 175°C junction temperature
- 4、 EAS condition: T_J=25°C, V_{DD}= -24V, V_G= -10V, R_G=7Ω, L=0.1mH, I_{AS}= -29A
- 5、 The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

N-Typical Characteristics

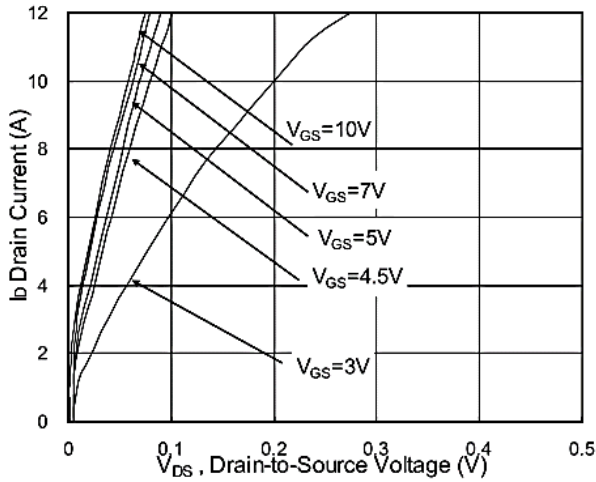


Fig.1 Typical Output Characteristics

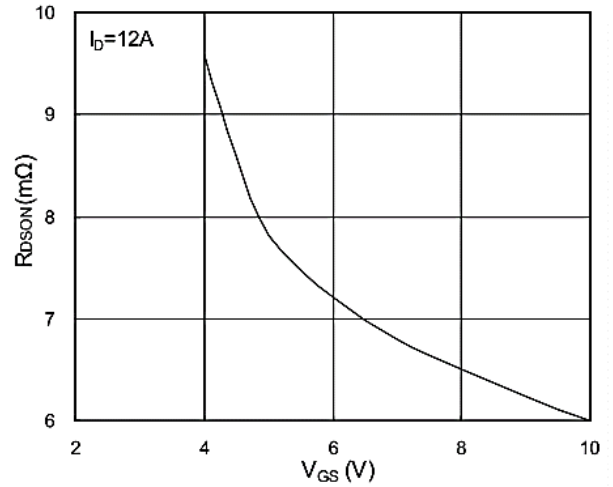


Fig.2 On-Resistance vs. G-S Voltage

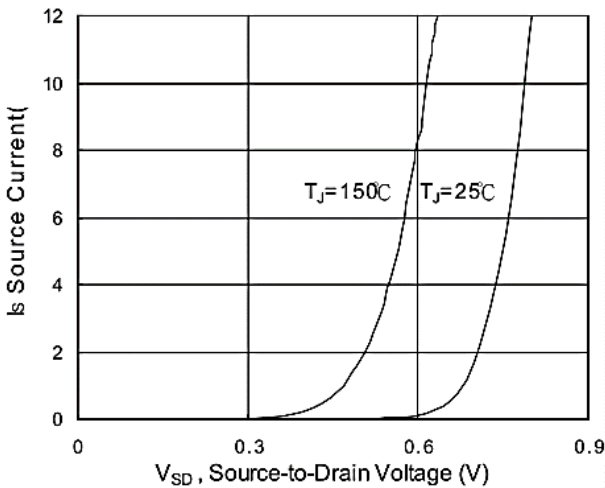


Fig.3 Forward Characteristics of Reverse

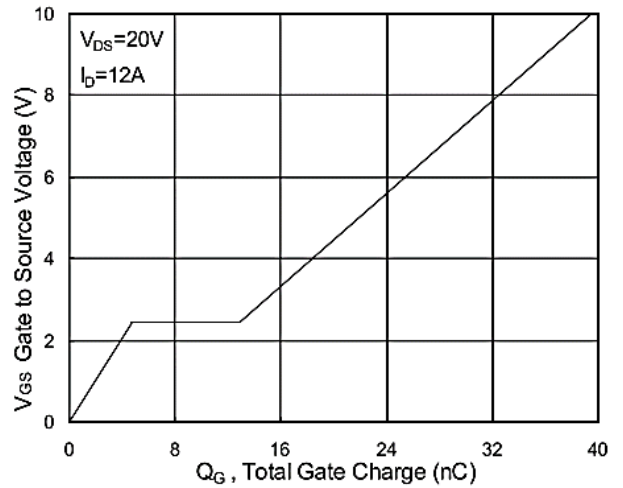


Fig.4 Gate-Charge Characteristics

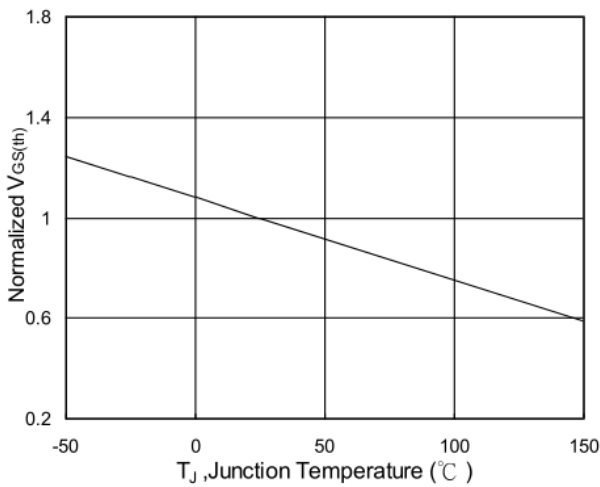


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

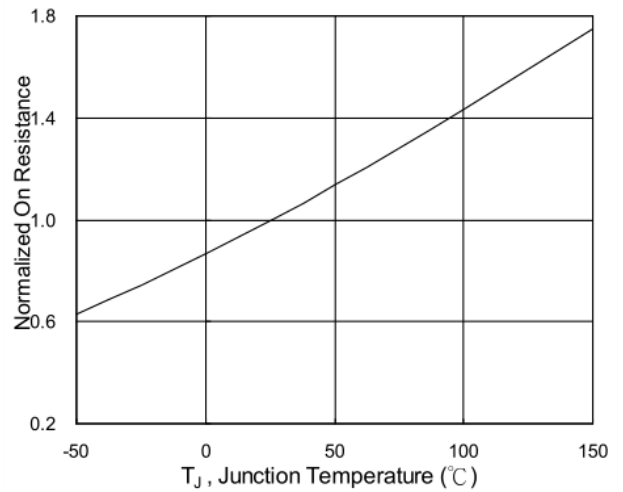


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

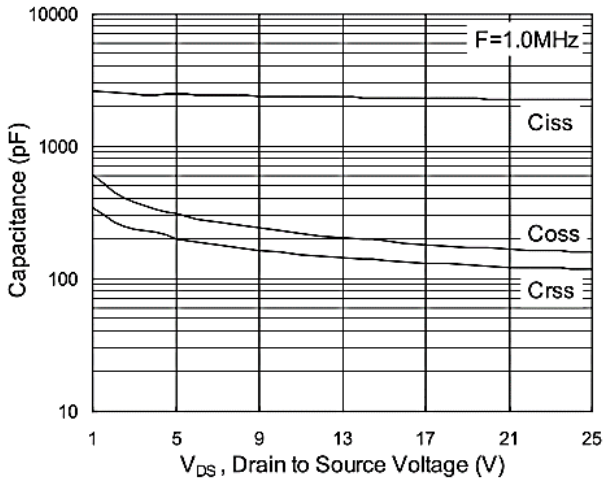


Fig.7 Capacitance

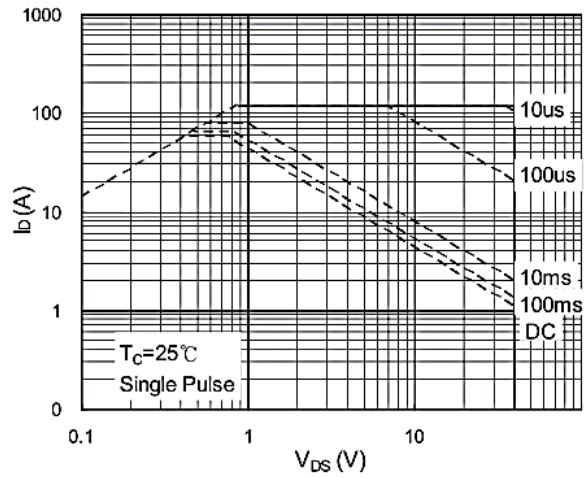


Fig.8 Safe Operating Area

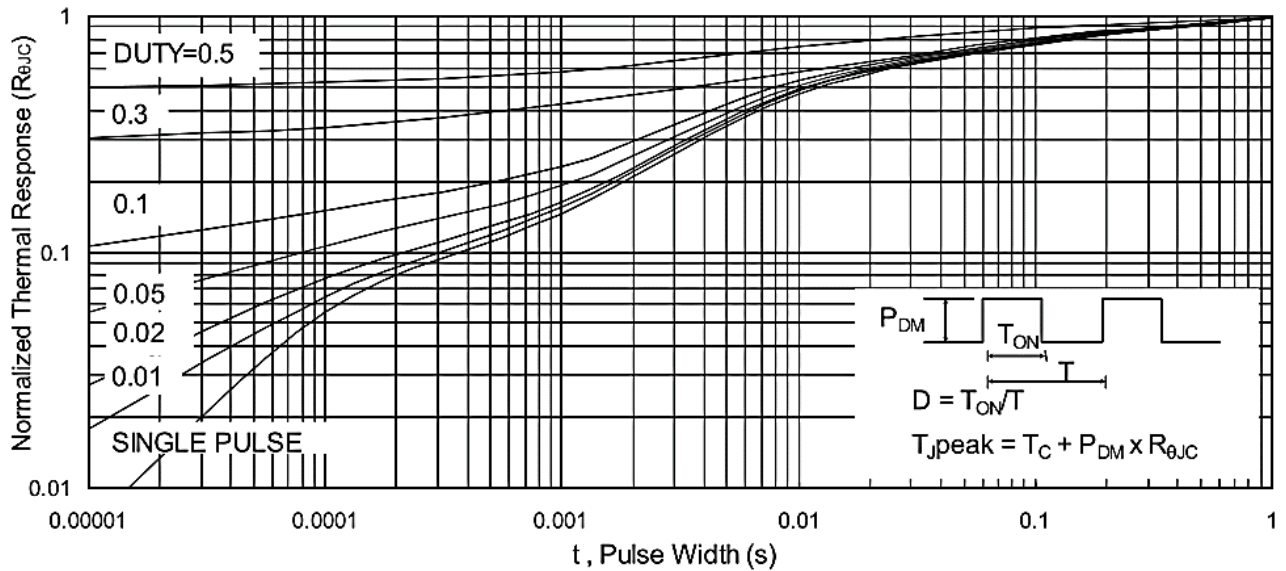


Fig.9 Normalized Maximum Transient Thermal Impedance

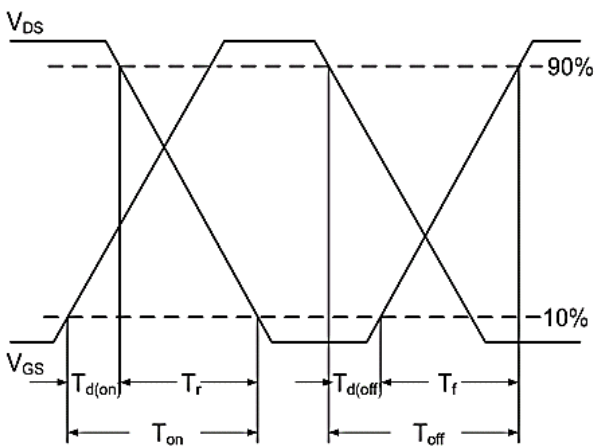


Fig.10 Switching Time Waveform

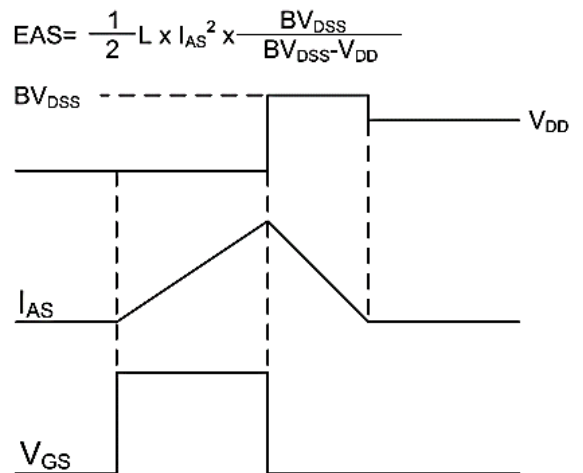


Fig.11 Unclamped Inductive Waveform

P-Typical Characteristics

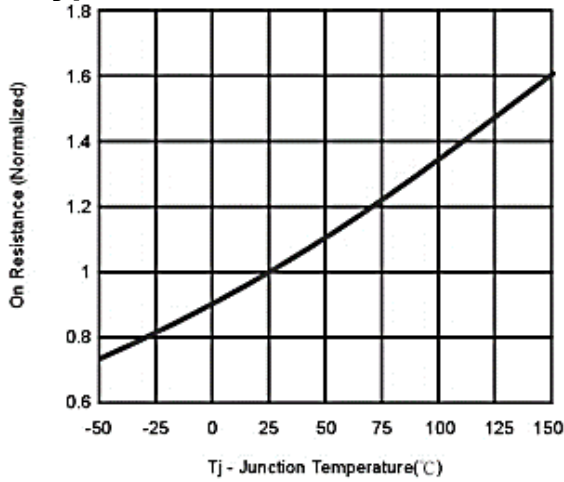


Fig.1 On Resistance Vs Junction Temperature

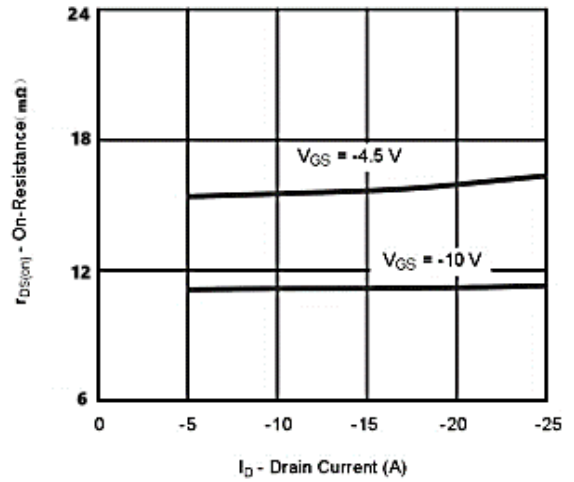


Fig.2 On-Resistance Vs. Drain Current

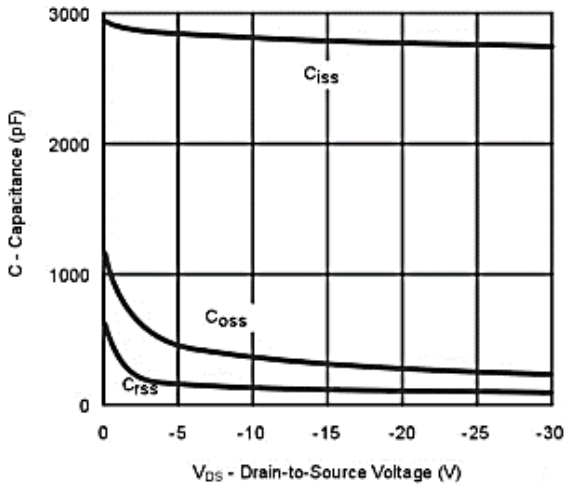


Fig.3 Capacitance

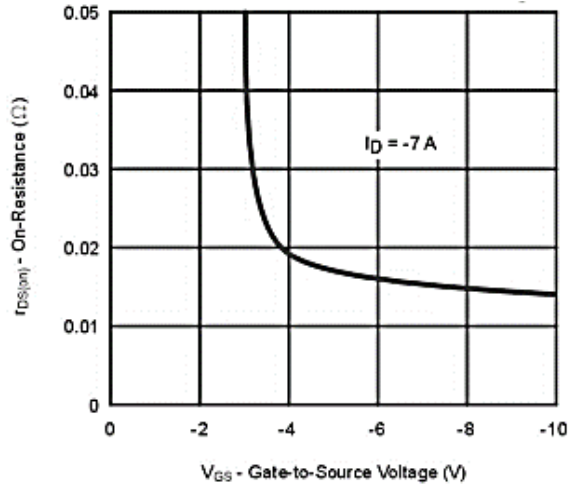


Fig.4 On-Resistance Vs. Gate-to-Source Voltage

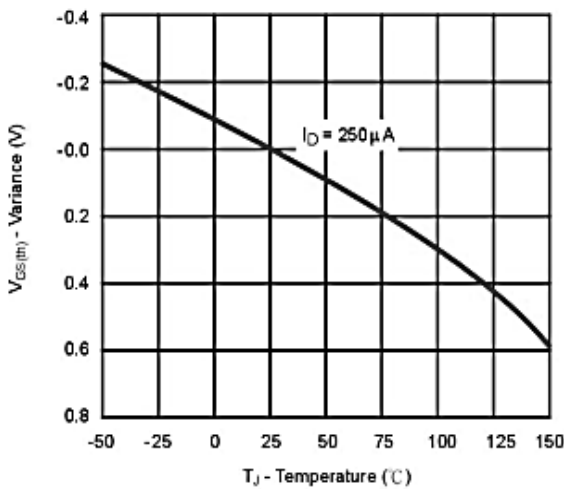


Fig.5 Threshold Voltage

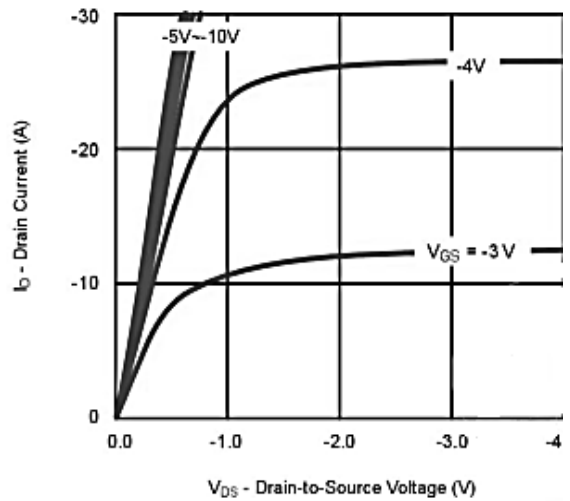


Fig.6 On-Region Characteristics

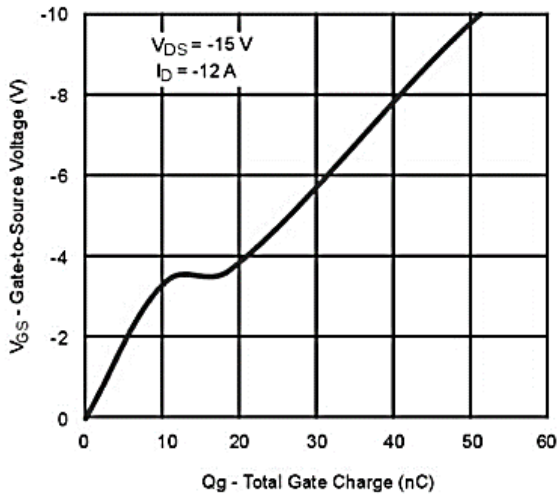


Fig.7 Gate Charge

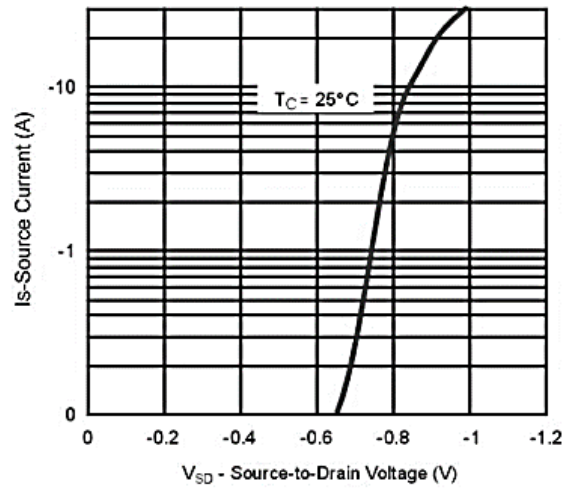


Fig.8 Body-diode Characteristic

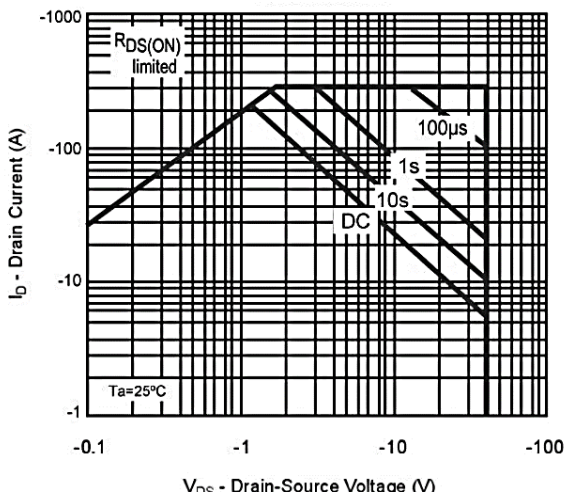


Fig.9 Safe Operating Area

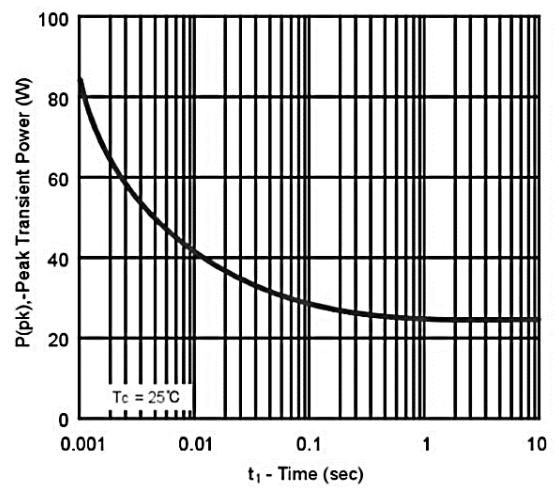


Fig.10 Single Pulse Maximum Power Dissipation

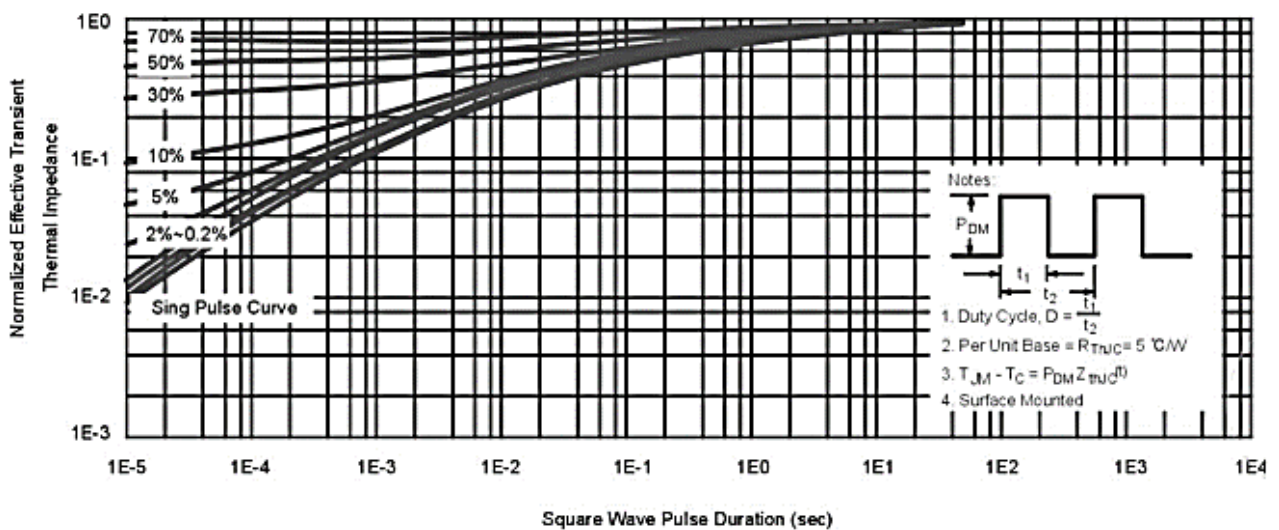
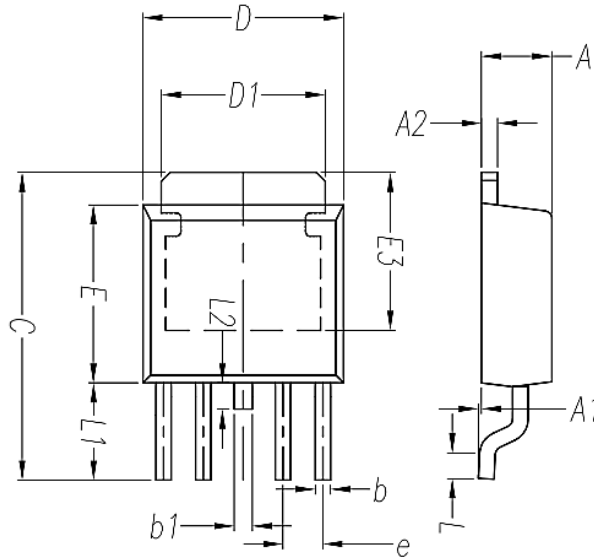


Fig.11 Normalized Maximum Transient Thermal Impedance

40V N+P-Channel Enhancement Mode MOSFET
Package Mechanical Data-TO-252-4L-Duble-DX


Symbol	Common		
	mm		
	Mim	Nom	Max
D	6.30	6.55	6.80
D1	4.80	5.35	5.90
C	9.70	10.00	10.30
E	5.90	6.10	6.30
E3	4.50	5.15	5.80
L	0.90	1.35	1.80
L1	2.60	2.85	3.05
L2	0.50	0.85	1.20
b	0.30	0.50	0.70
b1	0.40	0.60	0.80
A	2.10	2.30	2.50
A2	0.40	0.53	0.65
A1	0.00	0.10	0.20
e	1.17	1.27	1.37

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C±5°C	5sec±1 sec
Pb-Free device	260°C+0/-5°C	5sec±1 sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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